April 1992 Revised May 2005

### 74ABT16245 16-Bit Transceiver with 3-STATE Outputs

#### **General Description**

FAIRCHILD

SEMICONDUCTOR

The ABT16245 contains sixteen non-inverting bidirectional buffers with 3-STATE outputs and is intended for bus oriented applications. The device is byte controlled. Each byte has separate control inputs which can be shorted together for full 16-bit operation. The T/R inputs determine the direction of data flow through the device. The  $\overline{OE}$  inputs disable both the A and B ports by placing them in a high impedance state.

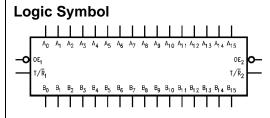
#### Features

- Bidirectional non-inverting buffers
- Separate control logic for each byte
- 16-bit version of the ABT245
- A and B output sink capability of 64 mA, source capability of 32 mA
- Guaranteed output skew
- Guaranteed multiple output switching specifications
   Output switching specified for both 50 pF and 250 pF loads
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability

#### **Ordering Code:**

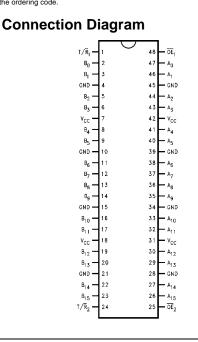
Order Number	Package Number	Package Description
74ABT16245CSSC	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide
74ABT16245CMTD	MTD48	48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.



#### **Pin Descriptions**

Pin Names	Description
OEn	Output Enable Input (Active LOW)
T/R <sub>n</sub>	Transmit/Receive Input
A <sub>0</sub> -A <sub>15</sub>	Side A Inputs/Outputs
B <sub>0</sub> -B <sub>15</sub>	Side B Inputs/Outputs



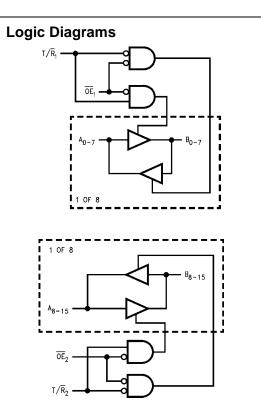
# 74ABT16245

#### **Truth Tables** Inputs Outputs OE<sub>1</sub> T/R<sub>1</sub> L L Bus B<sub>0</sub>-B<sub>7</sub> Data to Bus A<sub>0</sub>-A<sub>7</sub> L Н Bus A<sub>0</sub>-A<sub>7</sub> Data to Bus B<sub>0</sub>-B<sub>7</sub> Н Х HIGH-Z State on A<sub>0</sub>–A<sub>7</sub>, B<sub>0</sub>–B<sub>7</sub> Inputs Outputs OE<sub>2</sub> T/R<sub>2</sub> L L Bus $B_8$ – $B_{15}$ Data to Bus $A_8$ – $A_{15}$ L н Bus A<sub>8</sub>-A<sub>15</sub> Data to Bus B<sub>8</sub>-B<sub>15</sub> н х HIGH-Z State on $A_8\text{--}A_{15},\,B_8\text{--}B_{15}$ H = HIGH Voltage Level L = LOW Voltage Level

X = Immaterial Z = High Impedance

#### **Functional Description**

The ABT16245 contains sixteen non-inverting bidirectional buffers with 3-STATE outputs. The device is byte controlled with each byte functioning identically, but independent of the other. The control pins can be shorted together to obtain full 16-bit operation.



#### Absolute Maximum Ratings(Note 1)

Storage Temperature	–65°C to +150°C
Ambient Temperature under Bias	–55°C to +125°C
Junction Temperature under Bias	–55°C to +150°C
$V_{CC} Pin$ Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Any Output	
in the Disabled or	
Power-Off State	-0.5V to 5.5V
in the HIGH State	-0.5V to V <sub>CC</sub>
Current Applied to Output	
in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)
DC Latchup Source Current	–500 mA
Over Voltage Latchup (I/O)	10V

## Recommended Operating Conditions

Free Air Ambient Temperature	-40°C to +85°C
Supply Voltage	+4.5V to +5.5V
Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
Data Input	50 mV/ns
Enable Input	20 mV/ns

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

Symbol	Param	eter	Min	Тур	Max	Units	V <sub>cc</sub>	Conditions
VIH	Input HIGH Voltage		2.0			V	1	Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Volt	age	·		-1.2	V	Min	$I_{IN} = -18 \text{ mA} (\overline{OE}_n, T/\overline{R}_n)$
V <sub>OH</sub>	Output HIGH Voltage		2.5			V	Min	$I_{OH} = -3 \text{ mA} (A_n, B_n)$
			2.0			V	Min	$I_{OH} = -32 \text{ mA} (A_n, B_n)$
V <sub>OL</sub>	Output LOW Voltage				0.55	V	Min	$I_{OL} = 64 \text{ mA} (A_n, B_n)$
I <sub>IH</sub>	Input HIGH Current				1	μA	Max	$V_{IN} = 2.7V (\overline{OE}_n, T/\overline{R}_n) (Note 3)$
					1			$V_{IN} = V_{CC} (\overline{OE}_n, T/R_n)$
I <sub>BVI</sub>	Input HIGH Current Bre	akdown Test	i .		7	μA	Max	$V_{IN} = 7.0V \ (\overline{OE}_n, T/R_n)$
I <sub>BVIT</sub>	Input HIGH Current Bre	akdown Test (I/O)			100	μΑ	Max	$V_{IN} = 5.5V (A_n, B_n)$
IIL	Input LOW Current				-1	μA	Max	$V_{IN} = 0.5V (\overline{OE}_n, T/\overline{R}_n)$ (Note 3)
	l				-1			$V_{IN} = 0.0V (\overline{OE}_n, T/R_n)$
V <sub>ID</sub>	Input Leakage Test		4.75			V	0.0	$I_{ID} = 1.9 \ \mu A \ (\overline{OE}_n, \ T/\overline{R}_n)$
	ļ							All Other Pins Grounded
I <sub>IH</sub> + I <sub>OZH</sub>	Output Leakage Curren	ıt	L		10	μΑ	0 – 5.5V	$V_{OUT} = 2.7V (A_n, B_n); \overline{OE} = 2.0V$
I <sub>IL</sub> + I <sub>OZL</sub>	Output Leakage Curren	it	 I		-10	μA	0 – 5.5V	$V_{OUT} = 0.5V \text{ (A}_n\text{, B}_n\text{); } \overline{\text{OE}} = 2.0V$
I <sub>OS</sub>	Output Short-Circuit Cu	rrent	-100		-275	mA	Max	$V_{OUT} = 0.0V (A_n, B_n)$
I <sub>CEX</sub>	Output HIGH Leakage	Current			50	μΑ	Max	$V_{OUT} = V_{CC} (A_n, B_n)$
I <sub>ZZ</sub>	Bus Drainage Test				100	μΑ	0.0	V <sub>OUT</sub> = 5.50V (A <sub>n</sub> , B <sub>n</sub> ); All Others GND
I <sub>CCH</sub>	Power Supply Current				100	μA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current		. <u></u>		60	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current				100	μΑ	Max	$\overline{OE}_n = V_{CC}$ , T/ $\overline{R}_n = GND$ or $V_{CC}$ All others at $V_{CC}$ or GND
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input	Outputs Enabled			2.5	mA		$V_{I} = V_{CC} - 2.1V$
		Outputs 3-STATE	i .		2.5	mA	Max	$\overline{OE}_{n}$ , T/R <sub>n</sub> V <sub>I</sub> = V <sub>CC</sub> = 2.1V
		Outputs 3-STATE	i.		50	μA		Data Input $V_1 = V_{CC} - 2.1V$
			i					All others at V <sub>CC</sub> or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub>	No Load				mA/	Max	Outputs OPEN
	(Note 3)		i.		0.1	MHz		$\overline{OE}_n = GND, T/\overline{R}_n = GND \text{ or } V_{CC}$
l			1					One Bit Toggling, 50% Duty Cycle

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#### **DC Extended Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	v <sub>cc</sub>	Conditions C <sub>L</sub> = 50 pF; R <sub>L</sub> = 500 $\Omega$
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>		0.5	0.9	V	5.0	$T_A = 25^{\circ}C$ (Note 4)
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	-1.4	-1.0		V	5.0	$T_A = 25^{\circ}C$ (Note 4)
V <sub>OHV</sub>	Minimum HIGH Level Dynamic Output Voltage	2.5	3.0		V	5.0	$T_A = 25^{\circ}C$ (Note 5)
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	2.0	1.4		V	5.0	$T_A = 25^{\circ}C$ (Note 5)
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage		1.2	0.8	V	5.0	$T_A = 25^{\circ}C$ (Note 6)
Note 4: Max n	umber of outputs defined as (n). n - 1 data inputs are	driven 0V t	o 3V. One ou	tput at LOW	Guaranteed	d, but not te	sted.

Note 5: Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested. Note 6: Max number of data inputs (n) switching. n - 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>).

Guaranteed, but not tested.

#### **AC Electrical Characteristics**

Symbol	Parameter		$T_A = +25 \degree C$ $V_{CC} = +5V$ $C_L = 50 \ pF$		$T_{A} = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = 4.5V - 5.5V$ $C_{L} = 50 \text{ pF}$		$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V - 5.5V$ $C_{L} = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation	1.0	2.4	3.9	0.5	4.5	1.0	3.9	20
t <sub>PHL</sub>	Delay Data to Outputs	1.0	2.8	3.9	0.5	5.2	1.0	3.9	ns
t <sub>PZH</sub>	Output Enable	1.5	3.6	6.3	0.8	6.4	1.5	6.3	20
t <sub>PZL</sub>	Time	1.5	3.7	6.3	0.9	6.9	1.5	6.3	ns
t <sub>PHZ</sub>	Output Disable	1.3	4.6	6.9	1.3	6.9	1.3	6.9	
t <sub>PLZ</sub>	Time	1.3	3.7	6.9	1.0	6.9	1.3	6.9	ns

#### **Extended AC Electrical Characteristics**

		T <sub>A</sub>	=-40°C to +8	35°C	T <sub>A</sub> = -40°	C to +85°C	T <sub>A</sub> = -40°	C to +85°C	
Symbol		$V_{CC} = 4.5V$ –5.5V $C_L = 50 \text{ pF}$ 16 Outputs Switching			$V_{CC} = 4.5V-5.5V$ $C_L = 250 \text{ pF}$ 1 Output Switching (Note 8)		$\label{eq:V_CC} \begin{array}{l} V_{CC} = 4.5 \text{V} - 5.5 \text{V} \\ C_L = 250 \ \text{pF} \\ \hline 16 \ \text{Outputs} \ \text{Switching} \\ (\text{Note 9}) \end{array}$		Units
	Parameter								
	, and notes								
		(Note 7)							
		Min	Тур	Мах	Min	Max	Min	Max	
f <sub>TOGGLE</sub>	Maximum Toggle Frequency		100						MHz
t <sub>PLH</sub>	Propagation Delay	1.5		5.0	1.5	6.0	2.5	8.0	ns
t <sub>PHL</sub>	Data to Outputs	1.5		5.3	1.5	6.0	2.5	8.0	115
t <sub>PZH</sub>	Output Enable	1.5		6.5	2.5	8.2	2.5	10.0	ns
t <sub>PZL</sub>	Time	1.5		6.5	2.5	8.2	2.5	9.0	115
t <sub>PHZ</sub>	Output Disable	1.0		6.9	(Note 10)		(Note	a 10)	ns
t <sub>PLZ</sub>	Time	1.0		6.9			(Note 10)		115

Note 7: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 8: This specification is guaranteed but not tested. The limits represent propagation delay with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 9: This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 10: 3-STATE delay are dominated by the RC network (500Ω, 250 pF) on the output and have been excluded from the datasheet.

Symbol	Parameter	$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V-5.5V$ $C_{L} = 50 \text{ pF}$ 16 Outputs Switching (Note 11) Max	$T_{A} = -40 ^{\circ}\text{C to } +85 ^{\circ}\text{C}$ $V_{CC} = 4.5 \text{V} - 5.5 \text{V}$ $C_{L} = 250 \text{pF}$ 16 Outputs Switching (Note 12) Max	Units
t <sub>OSHL</sub> (Note 13)	Pin to Pin Skew HL Transitions	1.3	1.5	ns
t <sub>OSLH</sub> (Note 13)	Pin to Pin Skew LH Transitions	1.3	1.5	ns
t <sub>PS</sub> (Note 14)	Duty Cycle LH–HL Skew	1.5	2.0	ns
t <sub>OST</sub> (Note 13)	Pin to Pin Skew LH/HL Transitions	1.7	2.5	ns
t <sub>PV</sub> (Note 15)	Device to Device Skew LH/HL Transitions	2.0	3.0	ns

Note 11: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase

(i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.)

Note 12: These specifications guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 13: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH to LOW ( $t_{OSHL}$ ), LOW to HIGH ( $t_{OSLH}$ ), or any combination switching LOW-to-HIGH and/or HIGH-to-LOW ( $t_{OST}$ ). The specification is guaranteed but not tested.

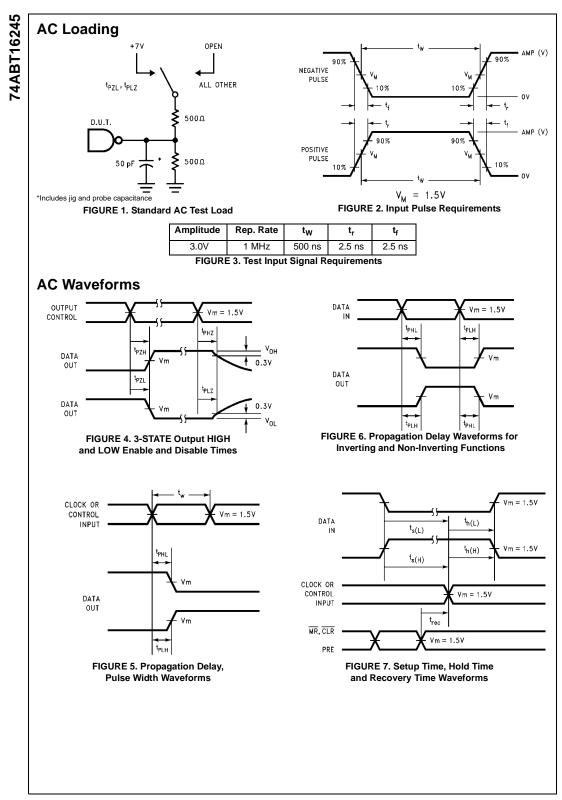
Note 14: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested. Note 15: Propagation delay variation for a given set of conditions (i.e., temperature and V<sub>CC</sub>) from device to device. This specification is guaranteed but not tested.

#### Capacitance

Symbol	Parameter	Тур	Units	Conditions T <sub>A</sub> = 25°C
C <sub>IN</sub>	Input Capacitance	5	pF	$V_{CC} = 0.0V \ (\overline{OE}_n, \ T/\overline{R}_n)$
CI/O (Note 16)	Output Capacitance	11	pF	$V_{CC} = 5.0V (A_n, B_n)$

Note 16:  $C_{I/O}$  is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.

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